

**Search Notes**

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Examiner

H.Jey Tsai

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2812

**SEARCHED**

Class	Subclass	Date	Examiner
438	243- 249,386- 392,713	3/11/2005	J

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
438	243	3/11/2005	J

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR